

PATENT

Docket No.: JCLA16514

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : HIROSHI SAWADA et al.  
Application No. : 10/529,376  
Filed : March 28, 2005  
For : METHOD OF FORMING A PERIODIC  
STRUCTURE AND SURFACE  
TREATMENT

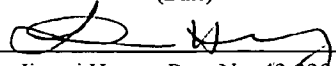
Group Art Unit :

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September 15, 2005

(Date)

  
Jiawei Huang, Reg. No. 43,330

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

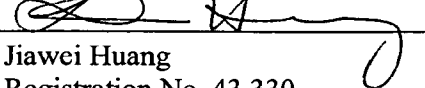
Enclosed is a PTO Form 1449 listing NINE ( 9 ) references, copy of which are attached. Applicants submit the reference(s) in compliance with their duty of disclosure pursuant to 37 CFR §1.56 and 1.97. The Examiner is requested to make the citation(s) of official record.

This IDS is being submitted before first Office Action. Thus, no fee is due. However, if a first Office Action has been sent, the Commissioner is authorized to charge any necessary fee in connection with the submission of the IDS to Account No. 50-0710 (Order No. JCLA16514).

The submission of the references should not be interpreted as admitting them as prior art.

Respectfully submitted,  
J.C. Patents

Dated: 9/15/2005

By:   
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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	ATTY. DOCKET NO.: JCLA16514	APPLICATION No.: 10/529,376
	APPLICANT: HIROSHI SAWADA et al.	
	FILING DATE: March 28, 2005	GROUP:

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
/SMH/	1	<b>"Incident-Angle Dependency of Laser-induced Surface Ripples on Metals and Semiconductors"</b> By Yukimasa Minami et al. / December 2000 Review of Laser Engineering Vol. 28, No. 12 / PP. 824-828 / <a href="http://www.soc.nii.ac.jp/ljsj/abstract/2000/V28No12_824.html">http://www.soc.nii.ac.jp/ljsj/abstract/2000/V28No12_824.html</a>
/SMH/	2	<b>"Fabrication of Micro-Gratings on Inorganic Materials by Two-Beam Holographic Method Using Infrared Femtosecond Laser Pulses"</b> By Ken-Ichi et al. / May 2002 Review of Laser Engineering Vol. 30, No. 5 / PP. 244-250 <a href="http://www.soc.nii.ac.jp/ljsj/abstract/2002/V30No05_0244.html">http://www.soc.nii.ac.jp/ljsj/abstract/2002/V30No05_0244.html</a>
/SMH/	3	<b>"Relations Among Friction and Pull-Off Forces and Surface Geometry in Nano Meter-Scale"</b> By Yasuhisa Ando et al. / September 1999 The Japan Society of Mechanical Engineers International Journal (C Series) Vol. 65, No. 637 / PP. 3784-3791
/SMH/	4	<b>"The effect of surface roughness on the adhesion of elastic solids"</b> By K. N. G. Fuller et al. / 1975 Proceedings of the Royal Society of London, Series A, Mathematical and Physical Sciences, Volume 345, Issue 1642 / PP. 327-342
/SMH/	5	<b>"Lubricated friction of laser micro-patterned sapphire flats"</b> By A. Blatter et al. / From September 1998 TRIBOLOGY LETTERS, publish by Springer Science+Business Media B.V., Formerly Kluwer Academic Publishers B.V., Volume 4, Numbers 3-4 / PP. 237 - 241
/SMH/	6	<b>"Periodic surface structures in the excimer laser ablative etching of polymers"</b> By P. E. Dyer et al. / August 20, 1990 Applied Physics Letters, Volume 57, Issue 8 / PP. 765-767
/SMH/	7	<b>"Laser-induced sub-half-micrometer periodic structure on polymer surfaces"</b> By Hiroyuki Hiraoka et al. / January 31, 1994 Applied Physics Letters, Volume 64, Issue 5 / PP. 563-565
/SMH/	8	<b>"Submicron periodic structures produced on polymer surfaces with polarized excimer laser ultraviolet radiation"</b> By Matthias Bolle et al. / February 10, 1992 Applied Physics Letters, Volume 60, Issue 6 / PP. 674-676
/SMH/	9	<b>"Stimulated Wood's Anomalies on Laser-Illuminated Surfaces"</b> By Anthony E. Siegman et al. / August 08, 1986 IEEE Journal of Quantum Electronics, Vol. 22, No. 8 / PP. 1384-1403

EXAMINER /Samuel M. Heinrich/ (08/18/2008)	DATE CONSIDERED 08/18/2008
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EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /SMH/